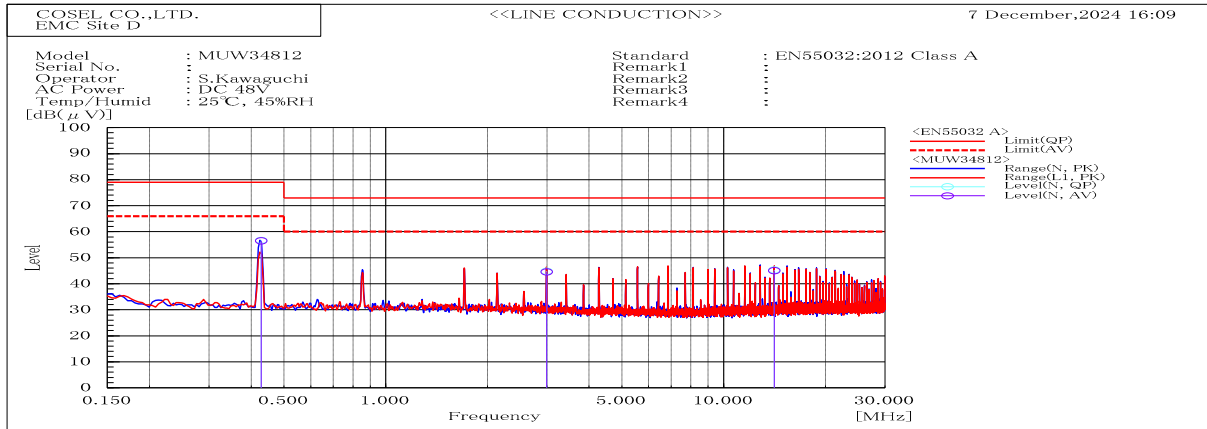
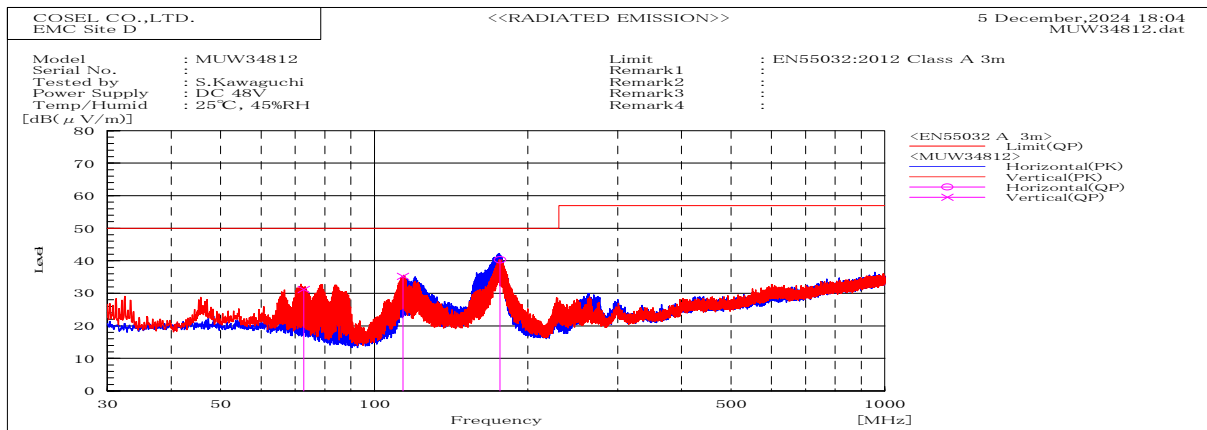


DATA SHEET

Date		07-Dec-24	
Model	MUW34812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi



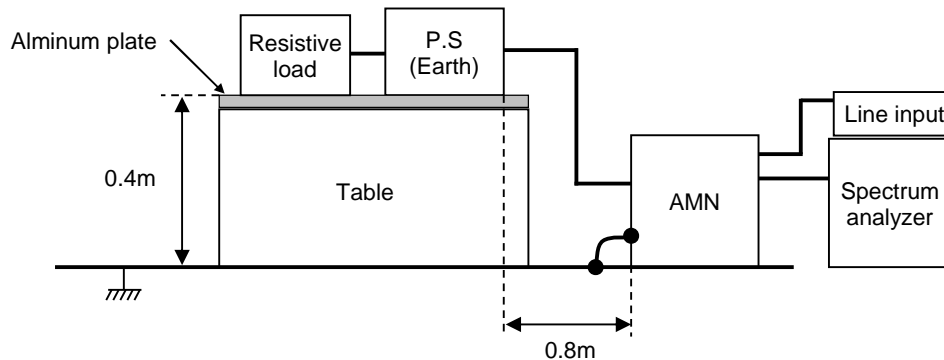
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.428	N	56.7	56.5	79	66	22.3	9.5	Pass	
2.996	N	44.8	44.6	73	60	28.2	15.4	Pass	
14.124	N	45.3	45	73	60	27.7	15	Pass	



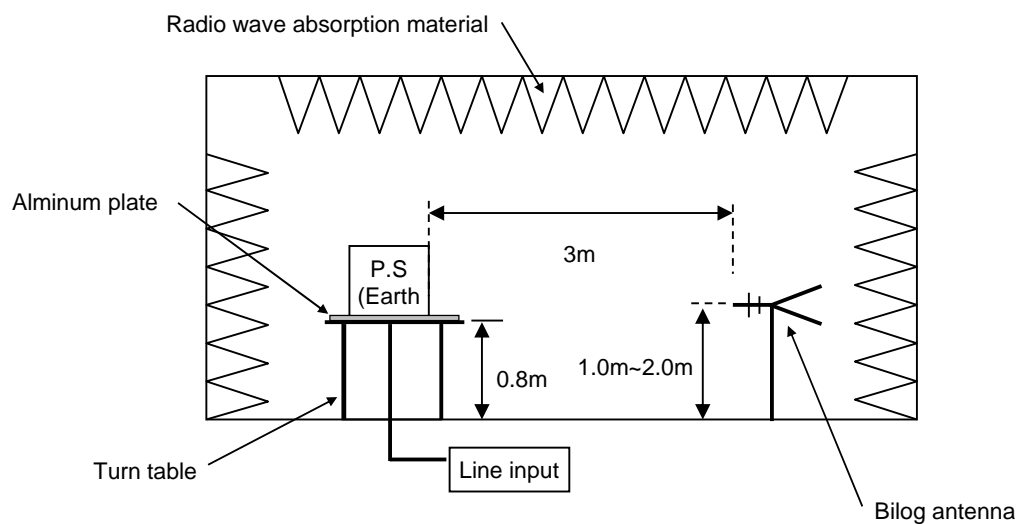
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP						
176.305	H	Stable	40.3	50	9.7	Pass	199.7	49.2		
113.832	V	Stable	35.2	50	14.8	Pass	100	281		
72.751	V	Stable	31.2	50	18.8	Pass	100	115.7		

DATA SHEET		Date	07-Dec-24
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

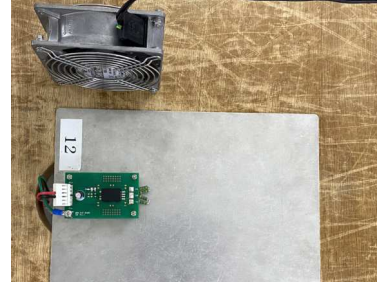
Test : EMI
Model Name: MUW3□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

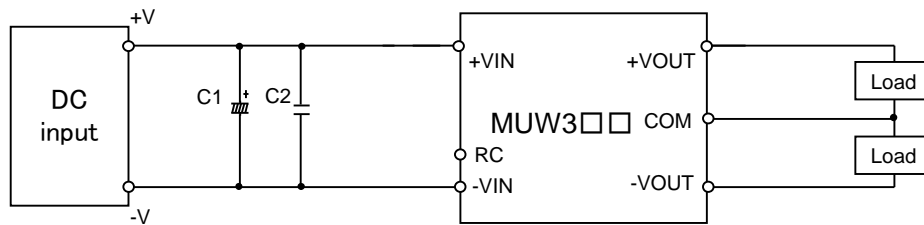


Fig.1 MUW305□, MUW312□, MUW324□ Testing circuitry

C1 :	MUW305□	16V 220 μ F	Electric capacitor (UPWseries NICHICON)
	MUW312□	50V 100 μ F	Electric capacitor (UPWseries NICHICON)
	MUW324□	-	
C2 :	MUW305□	16V 22 μ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUW312□	25V 22 μ F	Ceramic capacitor (C3216JB1E226MT TDK)
	MUW324□	50V 10 μ F	Ceramic capacitor (C3216X7R1H106KT TDK)

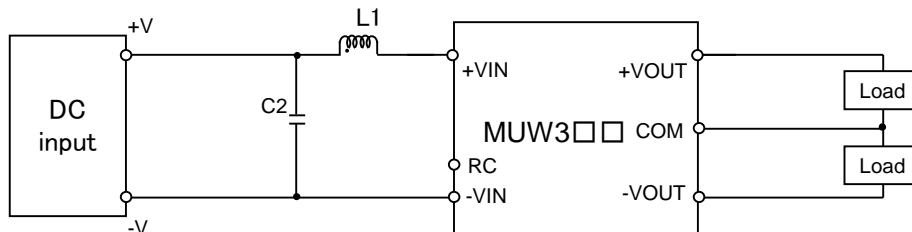


Fig.2 MUW348□ Testing circuitry

C2 :	MUW348□	100V 2.2 μ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUW348□	520mA 15 μ H	Inductor(LQH32PN150MN0L MURATA MANUFACTURING)